

## N-CHANNEL ENHANCEMENT-MODE LATERAL D-MOS FETs

### FEATURES

- High Gain—8.0dB min. @ 1GHz
- Low Noise—5.0dB max. @ 1GHz SD202, SD203
- Low Interelectrode Capacitances

### APPLICATIONS

- High-Gain VHF/UHF Amplifiers, Oscillators, and Mixers

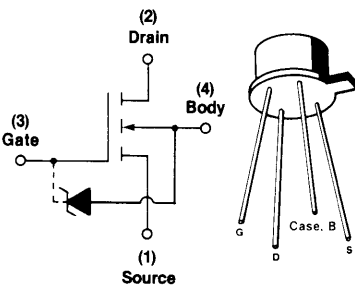
### ABSOLUTE MAXIMUM RATINGS (T<sub>A</sub> = +25 °C unless otherwise noted)

PARAMETER	SD200	SD201	SD202	SD203	UNIT		
<b>PARAMETER Breakdown Voltages</b>						I <sub>D</sub>	Continuous Drain Current . . . . . 50mA
V <sub>DS</sub>	+25	+25	+20	+20	Vdc	P <sub>T</sub>	Power Dissipation (at or below T <sub>C</sub> = +25 °C) . . . . . 1.8W
V <sub>DB</sub>	+25	+25	+20	+20	Vdc		Linear Derating Factor . . . . . 18 mW/°C
V <sub>GS</sub>	±40	-0.3	±40	-0.3	Vdc	P <sub>D</sub>	Power Dissipation (at or below T <sub>A</sub> = +25 °C) . . . . . 360mW
		+20		+20	Vdc		Linear Derating Factor . . . . . 3.6 mW/°C
V <sub>GB</sub>	±40	-0.3	±40	-0.3	Vdc	T <sub>j</sub>	Operating Junction Temperature Range . . -55 to +125 °C
		+20		+20	Vdc	T <sub>s</sub>	Storage Temperature Range . . . . . -65 to +175 °C
V <sub>GD</sub>	±40	-0.3	±40	+0.3	Vdc		
		+20		+20	Vdc		

### ORDERING INFORMATION

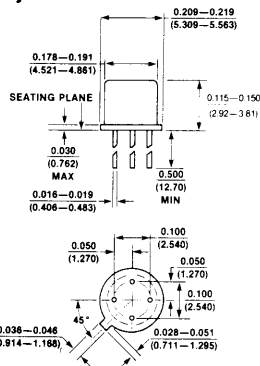
TO-52, 4 Lead Pkg.	SD200DC	SD201DC	SD202DC	SD203DC
Shorting Rings	SD200DC/R	SD201DC/R	SD202DC/R	SD203DC/R
Sorted Chips in Carriers	SD200CHP	SD201CHP	SD202CHP	SD203CHP

### SCHEMATIC DIAGRAM

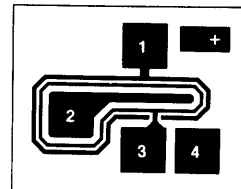


Body internally connected to Case.  
Diode protection on SD201/SD203 only.

### PACKAGE DIMENSIONS TO-52, 4-LEAD



### CHIP CONFIGURATION



- PAD**
- 1—Source
  - 2—Drain
  - 3—Gate
  - 4—Diode

For SD201-203CHP bond Gate and Diode to common point. Body is backside contact. Dimensions: .022 x .025 x .013 Inches

## SECTION 2

In addition to standard products listed in this section, a wide variety of special electrical selections are available to the user. Specials are available in the same packages as the basic standard products, including chip form. All special electrical selections, including these in chip form, are 100% tested to the selection criteria.

### PARAMETER SELECTOR GUIDE

Basic Chip	$BV_{DS}$ min (V)	$BV_{DSX}$ min (V)	$BV_{SDX}$ min (V)	$I_{D(off)}$ max (nA)	$I_{S(off)}$ max (nA)	$V_{GS(th)}$ min (V)	$V_{GS(th)}$ max (V)	$r_{DS(on)}$ max @ 5V (ohms)	$r_{DS(on)}$ max @ 5V (ohms)
SD200-201	25-30	—	—	10-1000	—	0.1-1.0	1.2-2.0	45-70	—
SD202-203	20-25	—	—	10-1000	—	0.1-1.0	1.2-2.0	35-50	—
SD205	25	—	—	100-1000	—	0.5-1.0	1.2-2.0	7.0-8.0	5.0-6.0
SD210-211	30-35	10-25	10-15	1.0-10	2.0-10	0.5-1.2	1.2-2.0	50-70	40-45
SD214-215	—	20-25	20	1.0-10	2.0-10	0.1-1.2	1.2-2.0	50-70	40-45
SD217	25	15-20	15-20	10-100	20-100	0.1-1.0	1.2-2.0	7.0-8.0	5.0-6.0
SD219	25	15-20	20	10-100	20-100	0.1-1.0	1.2-2.0	7.0-8.0	5.0-6.0
SD303	20-25	—	—	10-1000	—	0.1-0.5	1.5	65-80	—
SD304	25-30	—	—	10-1000	—	0.1-0.5	1.5-2.0	90-130	—
SD306	20-25	—	—	10-1000	—	0.1-0.5	1.5	65-100	—
SD2215	25-35	—	—	50-1000	—	0.5-1.2	1.2-2.0	30-35	22-25
SD5000	—	20-25	20	1.0-10	2.0-10	0.5-1.2	1.2-2.0	50-70	—
SD5001	—	10-25	10	1.0-10	2.0-10	0.5-1.2	1.2-2.0	50-70	—
SD5002	—	15-25	15	1.0-10	2.0-10	0.5-1.2	1.2-2.0	50-70	—
SD5100	30-35	—	—	1.0-10	-	0.5-1.0	1.2-2.0	50-70	40-45
SD5101	15-25	—	—	1.0-10	-	0.5-1.0	1.2-2.0	50-70	40-45
SD5200	30-35	—	—	10-10000	-	0.5-1.2	1.2-2.0	50-80	—

**Note:** Parameters such as Switching Times ( $t_{on}$ ,  $t_{off}$ ), capacitances (eg:  $C_{iss}$ ,  $C_{oss}$ ,  $C_{rss}$ ) Power Gain and Noise Figure are chip design or test circuit dependent and cannot be selected.

**ELECTRICAL CHARACTERISTICS** ( $T_A = +25^\circ\text{C}$  unless otherwise noted)

#	PARAMETER		SD200, SD201			SD202, SD203			UNIT	TEST CONDITIONS	
			MIN	TYP	MAX	MIN	TYP	MAX			
1	STATIC	$BV_{DS}$ Drain-Source Breakdown Voltage	25	30		20	25		V	$I_D = 1.0\mu\text{A}, V_{GS} = V_{BS} = 0$	
2		$BV_{DB}$ Drain-Substrate Breakdown Voltage	25			20				$I_D = 1.0\mu\text{A}, V_{GB} = 0$ Source OPEN	
3		$I_{D(off)}$ Drain-Source OFF Current			1.0				$\mu\text{A}$	$V_{DS} = 25\text{V}$	$V_{GS} = V_{BS} = 0$
4							1.0			$V_{DS} = 20\text{V}$	
5		$I_{GBS}$ Gate-Body Leakage Current	SD200		$\pm 0.1$				nA	$V_{GB} = \pm 40\text{V}$	$V_{DB} = V_{SB} = 0$
6			SD202					$\pm 0.1$			
7			SD201		1.0				$\mu\text{A}$	$V_{GB} = 20\text{V}$	
8			SD203					1.0			
9		$V_{GS(th)}$ Gate Threshold Voltage	0.1	1.0	2.0	0.1	1.0	2.0	V	$V_{DS} = V_{GS}, I_D = 1\mu\text{A}, V_{SB} = 0$	
10		$r_{DS(on)}$ Drain-Source ON Resistance		40	70		35	50	ohms	$V_{GS} = 5\text{V}, I_D = 1\text{mA}, V_{SB} = 0$	
11		DYNAMIC	$g_{fs}$ Common-Source Forward Transcond.	13	14		17	20		mmhos	$I_D = 20\text{mA}, V_{DS} = 15\text{V}, f = 1\text{KHz}, V_{SB} = 0$
12			$c_{iss}$ Common-Source Input Capacitance		2.4	3.0		3.0	3.6	pF	$I_D = 20\text{mA}, V_{GS} = 0, V_{DS} = 15\text{V}, f = 1\text{MHz}, V_{SB} = 0$
13			$c_{oss}$ Common-Source Output Capacitance		1.0	1.2		1.0	1.2		
14			$c_{rss}$ Common-Source Reverse Transfer Capacitance		0.2	0.3		0.2	0.3		
15			$G_{ps}$ Common-Source Power Gain	8.0	10		8.0	10		dB	$V_{DS} = 15\text{V}, f = 1\text{GHz}, I_D = 20\text{mA}, V_{SB} = 0$
16			NF Noise Figure		4.5	6.0		4.0	5.0		
17			$P_i$ Intercept Point		29			29			

## N-CHANNEL ENHANCEMENT-MODE D-MOS POWER FET

### ORDERING INFORMATION

TO-72 Package	SD217DE	SD219DE
Shorting Ring	SD217DE/R	SD219DE/R
Sorted Chips in Waffle Pack	SD217CHP	SD219CHP
Description	6.0 ohm, 25V $V_{SB} = 15V$ min	6.0 ohm, 25V $V_{SB} = 20V$ min

### FEATURES

- CMOS Compatible Input
- Small Package, Standard Pin-Out
- TTL and CMOS Compatible Input
- Low Capacitance
- Peak Pulsed Current, 1 Amp min

### APPLICATIONS

- $\pm 10V$  Analog Switch, SD219DE
- $\pm 7.5V$  Analog Switch, SD217DE
- High Speed, Medium Power, Switch Drivers
- Sample and Hold and Track and Hold
- A-to-D and D-to-A Converters

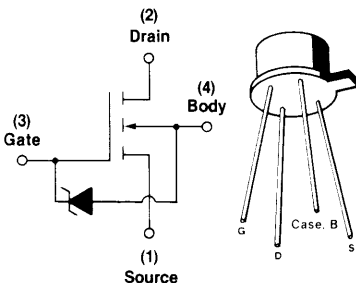
### ABSOLUTE MAXIMUM RATINGS ( $T_A = +25^\circ C$ unless otherwise specified)

$V_{DS}$ Drain-Source Voltage	+25V
$V_{DB}$ Drain-Body Voltage	
SD217	+22.5V
SD219	+25V
$V_{SD}$ Source-Drain Voltage	
SD217	+15V
SD219	+20V
$V_{SB}$ Source-Body Voltage	
SD217	+22.5V
SD219	+25V
$V_{GB}$ Gate-Body Voltage	+30V
$V_{GS}$ Gate-Source Voltage	$\pm 22.5V$
$V_{GD}$ Gate-Drain Voltage	$\pm 22.5V$
$I_D$ Peak Pulsed Drain Current	+1.0A

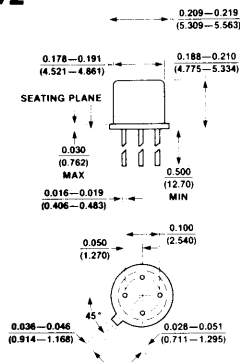
$I_D$ Continuous Drain Current (Note 1)	160mA
$P_D$ Continuous Power Dissipation (Note 1)	
$T_A = +25^\circ C$ (Free Air)	300mW
$T_C = +25^\circ C$ (Infinite Heat Sink)	1.2W
Power Derating Factors (Note 1)	
Free Air	3.0mW/ $^\circ C$
Infinite Heat Sink	12mW/ $^\circ C$
Thermal Resistance (Note 1)	
$\theta_{ja}$ Junction to Ambient	333 $^\circ C/W$
$\theta_{jc}$ Junction to Case	83 $^\circ C/W$
$T_{op}$ Operating Junction Temperature Range	-55 to +125 $^\circ C$
$T_{stg}$ Storage Temperature Range	-55 to +150 $^\circ C$

**Note 1:** Not applicable to chips. Final value depends on mounting.

### SCHEMATIC DIAGRAM

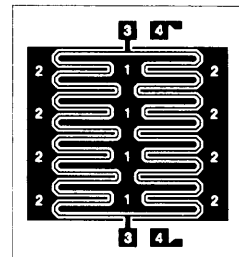


### PACKAGE DIMENSIONS TO-72



All dimensions in inches and (millimeters)

### CHIP CONFIGURATION



1—Drain 2—Source 3—Gate 4—Diode  
Minimum bonding required. One Drain, One Source (left), One Source (right), One Gate. Bond Gate and Adjacent Diode to Common Point to Connect Protective Diode.

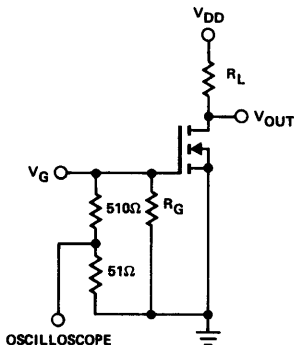
Size: .040 x .044 x .013 inch.  
Body (Substrate) is backside contact.

**ELECTRICAL CHARACTERISTICS** ( $T_A = +25^\circ\text{C}$  unless otherwise specified)

#	CHARACTERISTIC		MIN	TYP	MAX	UNITS	TEST CONDITIONS	
1	BV <sub>DS</sub>	Drain-Source Breakdown Voltage	25	30		V	I <sub>D</sub> = 10μA, V <sub>GS</sub> = V <sub>BS</sub> = 0	
2			15	20			I <sub>D</sub> = 100nA, V <sub>GS</sub> = V <sub>BS</sub> = -5V	
3	BV <sub>SD</sub>	Source-Drain Breakdown Voltage	SD217	15		V	I <sub>S</sub> = 100nA, V <sub>GD</sub> = V <sub>BD</sub> = -5V	
4			SD219	20				
5	BV <sub>DB</sub>	Drain-Body Breakdown Voltage	SD217	22.5		V	I <sub>D</sub> = 100nA, V <sub>GB</sub> = 0, Source Open	
6			SD219	25				
7	BV <sub>SB</sub>	Source-Body Breakdown Voltage	SD217	22.5		V	I <sub>S</sub> = 100nA, V <sub>GB</sub> = 0, Drain Open	
8			SD219	25				
9	STATIC	I <sub>D(off)</sub>	Drain-Source OFF Leakage Current		100	nA	V <sub>DS</sub> = 15V, V <sub>GS</sub> = V <sub>BS</sub> = -5V	
10		I <sub>S(off)</sub>	Source-Drain OFF Leakage Current		100		V <sub>SD</sub> = 15V, V <sub>GD</sub> = V <sub>BD</sub> = -5V	
11		I <sub>GB</sub>	Gate-Body ON Leakage Current		10		μA	V <sub>GB</sub> = 30V, V <sub>GS</sub> = V <sub>GD</sub> = 22.5V
12	V <sub>GS(th)</sub>	Gate-Source Threshold Voltage		0.1	2.0	V	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 10μA, V <sub>SB</sub> = 0	
13	I <sub>D(on)</sub>	Drain-Source ON Current (Note 1)		1.0		A	V <sub>DS</sub> = V <sub>GS</sub> = 10V, V <sub>SB</sub> = 0	
14	r <sub>DS(on)</sub>	Drain-Source ON Resistance (Note 1)			8.0	ohms	V <sub>GS</sub> = 5.0V	I <sub>D</sub> = 50mA
15					6.0			V <sub>SB</sub> = 0
16					6.0		V <sub>GS</sub> = 10V	I <sub>D</sub> = 500mA
17	g <sub>fs</sub>	Common-Source (Note 1) Forward Transconductance		100		mmhos	V <sub>DS</sub> = 15V, I <sub>D</sub> = 200mA V <sub>SB</sub> = 0, F = 1KHz	
18	C <sub>(gs + gd + gb)</sub>	Gate Node Capacitance			30	pF	V <sub>DS</sub> = 10V, V <sub>GS</sub> = V <sub>BS</sub> = -15V f = 1MHz	
19	C <sub>(gd + db)</sub>	Drain-Node Capacitance			15			
20	C <sub>(gs + sb)</sub>	Source Node Capacitance			40			
21	C <sub>(dg)</sub>	Reverse Transfer Capacitance			5.0			
22	t <sub>on</sub>	Turn ON Time		2.0	4.0			
23	t <sub>off</sub>	Turn OFF Time		3.0	5.0			

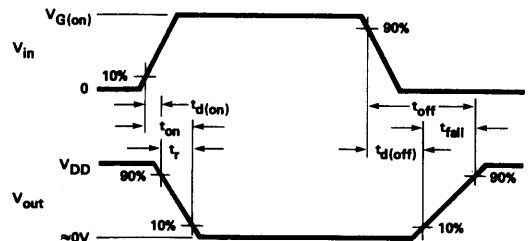
Note 1: Pulse Test 80μSec, 1% Duty Cycle

**SWITCHING TIMES TEST CIRCUIT**



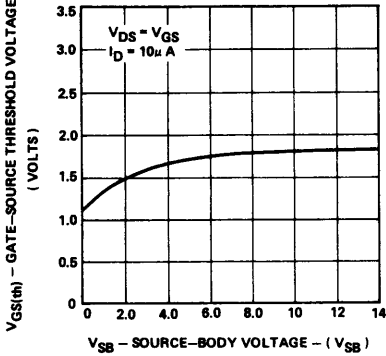
INPUT PULSE  
 $t_r < 0.5 \text{ nSEC}$   
 PULSE WIDTH - 100 nSEC  
 SAMPLING OSCILLOSCOPE  
 $t_r < 0.36 \text{ nSEC}$   
 $R_{in} > 1\text{M}\Omega$   
 $C_{in} < 2.0 \text{ pF}$

**TEST WAVEFORMS**

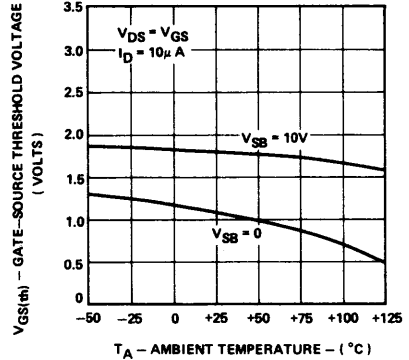


**TYPICAL PERFORMANCE CHARACTERISTICS** ( $T_A = +25^\circ\text{C}$  unless otherwise specified)

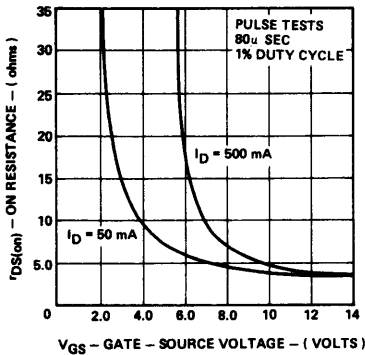
**GATE-SOURCE THRESHOLD VOLTAGE**  
—VS—  
**SOURCE-BODY VOLTAGE**



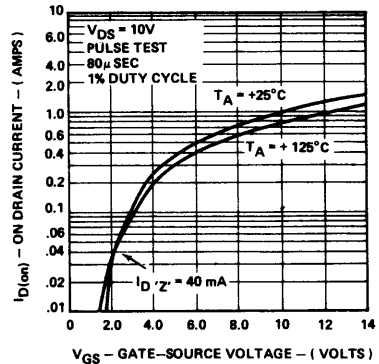
**GATE-SOURCE THRESHOLD VOLTAGE**  
—VS—  
**TEMPERATURE**



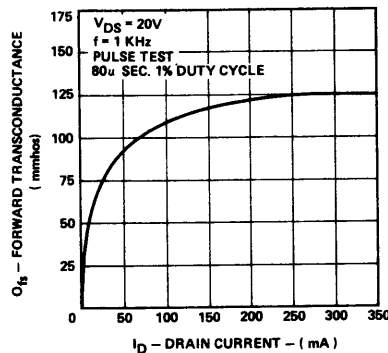
**DRAIN-SOURCE ON RESISTANCE**  
—VS—  
**GATE-SOURCE VOLTAGE**



**ON DRAIN CURRENT**  
—VS—  
**GATE-SOURCE VOLTAGE**



**FORWARD TRANSCONDUCTANCE**  
—VS—  
**ON DRAIN CURRENT**



## N-CHANNEL ENHANCEMENT-MODE DUAL GATE D-MOS FET

### FEATURES

- Normally Off-Enhancement-Mode Operation
- Dual Gate with Gate Protective Diodes
- Low Feedback Capacitance —  $C_{rss}$  .02pF (typ)
- Wide Dynamic Range-Remote AGC capability
- High Power Gain- 10dB min. @ 1GHz
- Low Noise-7.0dB max. @ 1GHz
- Low Cross-Modulation Distortion

### APPLICATIONS

- Wide Band (Unneutralized) VHF/UHF Amplifiers
- VHF/UHF Linear Mixers

### ABSOLUTE MAXIMUM RATINGS ( $T_A = +25^\circ\text{C}$ unless otherwise noted)

$V_{DS}$	Drain-Source Voltage	.....	+20V
$V_{G1B}$	Gate 1-Substrate Voltage	.....	-0.3 to +10V
$V_{G2B}$	Gate 2-Substrate Voltage	.....	-0.3 to +15V
$I_D$	Continuous Drain Current (Note 1)	.....	50mA
$P_D$	Continuous Power Dissipation (Note 1)		
	$T_A = +25^\circ\text{C}$ (Free Air)	.....	360mW
	$T_C = +25^\circ\text{C}$ (Infinite Heat Sink)	.....	1.8W
	Power Derating Factors (Note 1)		
	Free Air	.....	3.6mW/°C
	Infinite Heat Sink	.....	18mW/°C

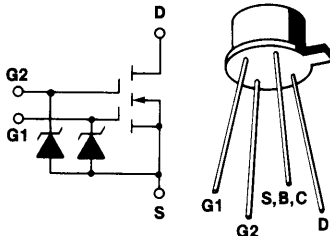
$T_{op}$	Operating Junction Temperature Range	.....	-55 to +125°C
$T_{stg}$	Storage Temperature Range	..	-65 to +175°C

**Note 1:** Not applicable to chips. Final value depends mounting substrate.

### ORDERING INFORMATION

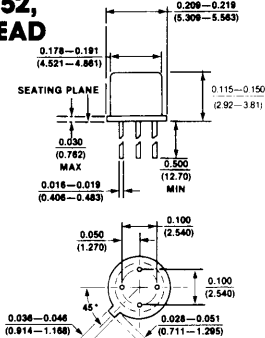
Sorted Chips in Carriers	SD303CHP
TO-52, 4 Lead Package	SD303DC
Shorting Rings	SD303DC/R

### SCHEMATIC DIAGRAM



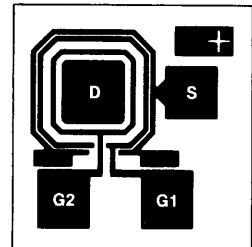
Pin 1-Drain, 2-Gate 2  
Pin 3-Gate 1,  
Pin 4-Source, Substrate, Case

### PACKAGE DIMENSIONS TO-52, 4 LEAD



All dimensions in inches and (millimeters)

### CHIP CONFIGURATION



Chip backside connected to source  
Dimensions: .022 x .022 x .013 inches

**ELECTRICAL CHARACTERISTICS** (TA = +25 °C unless otherwise noted)

#	PARAMETER		SD303			UNIT	TEST CONDITIONS	
			MIN	TYP	MAX			
1	BV <sub>DS</sub>	Drain-Source Breakdown Voltage	20	25		V	I <sub>D</sub> = 5μA V <sub>G1S</sub> = V <sub>G2S</sub> = 0	
2	I <sub>DSS</sub>	Drain-Source OFF Leakage Current		.01	1.0	μA	V <sub>DS</sub> = 15V V <sub>G1S</sub> = V <sub>G2S</sub> = 0	
3	I <sub>G1SS</sub>	Gate 1 Leakage Current		1.0	100	nA	V <sub>G1S</sub> = 5V V <sub>G2S</sub> = V <sub>DS</sub> = 0	
4	I <sub>G2SS</sub>	Gate 2 Leakage Current		1.0	100	nA	V <sub>G2S</sub> = 10V V <sub>G1S</sub> = V <sub>DS</sub> = 0	
5	V <sub>T1</sub>	Gate 1-Source Threshold Voltage	0.1	0.5	1.5	V	V <sub>DS</sub> = V <sub>G1S</sub> V <sub>G2S</sub> = 10V, I <sub>D</sub> = 1μA	
6	V <sub>T2</sub>	Gate 2-Source Threshold Voltage	0.1	0.5	1.5	V	V <sub>G1S</sub> = 4V	V <sub>DS</sub> = V <sub>G2S</sub> I <sub>D</sub> = 1μA
7	r <sub>DS(on)</sub>	Drain-Source ON Resistance		65	80	ohms	I <sub>D</sub> = 1mA, V <sub>G1S</sub> = 5V V <sub>G2S</sub> = 10V	
8	g <sub>fs</sub>	Common-Source Forward Transconductance	13	15		mmhos	V <sub>DS</sub> = 15V, I <sub>D</sub> = 18mA V <sub>G2S</sub> = 10V, f = 1KHz	
9	C <sub>iss</sub>	Common-Source Input Capacitance		3.0	3.5	pF	V <sub>DS</sub> = 15V, I <sub>D</sub> = 18mA V <sub>G2S</sub> = 10V, f = 1MHz	
10	C <sub>oss</sub>	Common-Source Output Capacitance		0.6		pF	V <sub>DS</sub> = 15V, V <sub>G1S</sub> = 0 V <sub>G2S</sub> = 10V, f = MHz	
11	C <sub>rss</sub>	Common-Source Reverse Transfer Capacitance		.02		pF		
12	G <sub>ps</sub>	Power Gain	10	14		dB	f = 1GHz	V <sub>DS</sub> = 15V V <sub>G2S</sub> = 10V I <sub>D</sub> = 18mA
13	NF	Noise Figure		5.5	7.0	dB	f = 1GHz	
14	AGC (V <sub>G2S</sub> )	Range of Automatic Gain Control		40		dB	V <sub>G1S</sub> ≅ 2.5V f = 500MHz	V <sub>DS</sub> = 15V V <sub>G2S</sub> = 10V to 0V
15	E <sub>INT</sub>	Interfering Signal at Gate for 1% Cross-Modulation Distortion (Peak Voltage ref. to 300 ohm system)		150		mV	f <sub>o</sub> = 1.000GHz f <sub>i</sub> = 0.995GHz	V <sub>DS</sub> = 15V V <sub>G2S</sub> = 10V I <sub>D</sub> = 18mA